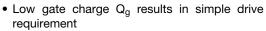


N-Channel 600V (D-S) Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	600				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 0.8				
Q _g max. (nC)	49				
Q _{gs} (nC)	13				
Q _{gd} (nC)	20				
Configuration	Single				

FEATURES

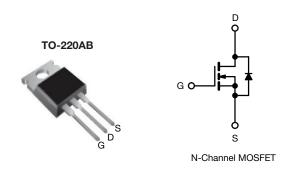




• Improved gate, avalanche and dynamic dV/dt

ruggedness

• Fully characterized capacitance and avalanche voltage and current



APPLICATIONS

- Switch mode power supply (SMPS)
- Uninterruptible power supply
- · High speed power switching

APPLICABLE OFF LINE SMPS TOPOLOGIES

- · Active clamped forward
- Main switch

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	600		
Gate-Source Voltage			V_{GS}	± 30	V	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	- I _D	8.0	А	
Continuous Drain Current		T _C = 100 °C		5.8		
Pulsed Drain Current ^a			I _{DM}	37		
Linear Derating Factor				1.3	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	290	mJ	
Repetitive Avalanche Current ^a			I _{AR}	8.0	Α	
Repetitive Avalanche Energy ^a			E _{AR}	17	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	170	W	
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak temperature) d for 10 s				300]	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Starting T_J = 25 °C, L = 6.8 mH, R_g = 25 Ω , I_{AS} = 9.2 A (see fig. 12). c. I_{SD} \leq 9.2 A, dI/dt \leq 50 A/µs, V_{DD} \leq V_{DS}, T_J \leq 150 °C.
- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.75			

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static		•					
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referen	Reference to 25 °C, I _D = 1 mA		660	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS}	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 30 V		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 600 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 5.5 \text{ A}^b$	-	0.8	-	Ω
Forward Transconductance	9 _{fs}		= 50 V, I _D = 5.5 A	5.5	-	-	S
Dynamic	<u> </u>					<u> </u>	
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	1400	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	180	-	
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		7.1	-	pF
Output Capacitance	C _{oss}	V _{GS} = 0 V	V _{DS} = 1.0 V, f = 1.0 MHz	-	1957	-	- pr
			V _{DS} = 480 V, f = 1.0 MHz	-	49	-	
Effective Output Capacitance	C _{oss} eff.		V _{DS} = 0 V to 480 V	-	96	-	
Total Gate Charge	Q_g		1 0 0 0 1 1 100 1	-	-	49	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V	$I_D = 8.0A$, $V_{DS} = 400 V$ see fig. 6 and 13 b	-	-	13	
Gate-Drain Charge	Q_{gd}		see lig. o and 15	=	-	20	
Turn-On Delay Time	t _{d(on)}			-	13	-	
Rise Time	t _r	V _{DD} = 300 V, I _D = 8.0 A		-	25	-	no
Turn-Off Delay Time	t _{d(off)}	$R_a = 9.1 \Omega$.	$R_D = 35.5 \Omega$, see fig. 10 b	-	30	-	ns
Fall Time	t _f	1 rig = 3.1 sz, rip = 33.3 sz, see rig. 10 ·		-	22	-	
Gate Input Resistance	R_g	f = 1 MHz, open drain		0.5	-	3.2	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	9.2	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	37	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 8.0 A, V _{GS} = 0 V b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 8.0 A, dI/dt = 100 A/μs b		-	530	800	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	3.0	4.4	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width $\leq 300~\mu s$; duty cycle $\leq 2~\%$. c. C_{oss} effective is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

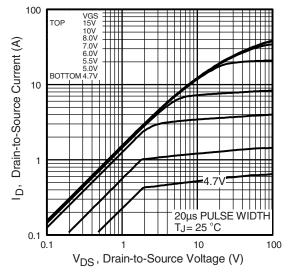


Fig. 1 - Typical Output Characteristics

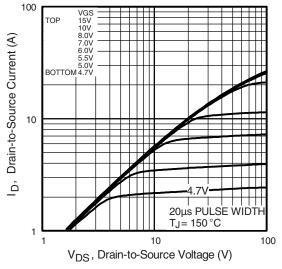


Fig. 2 - Typical Output Characteristics

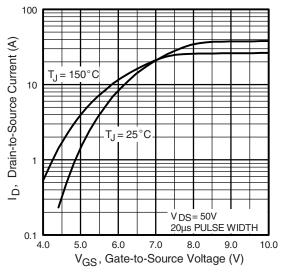


Fig. 3 - Typical Transfer Characteristics

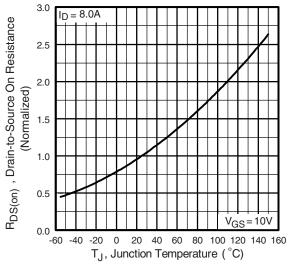


Fig. 4 - Normalized On-Resistance vs. Temperature



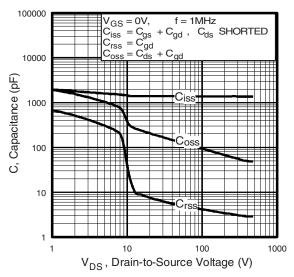


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

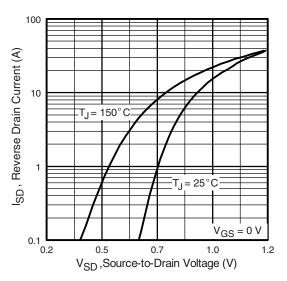


Fig. 7 - Typical Source-Drain Diode Forward Voltage

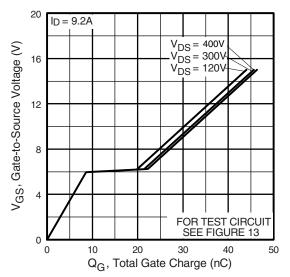


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

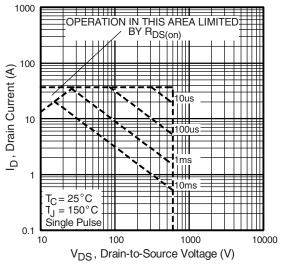


Fig. 8 - Maximum Safe Operating Area



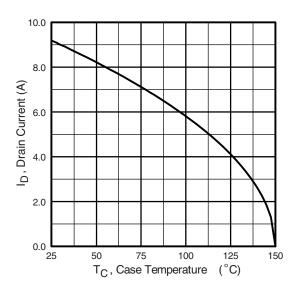


Fig. 9 - Maximum Drain Current vs. Case Temperature

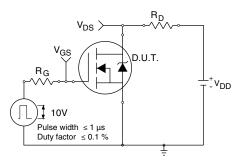


Fig. 10a - Switching Time Test Circuit

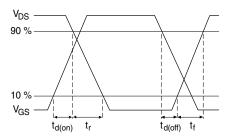


Fig. 10b - Switching Time Waveforms

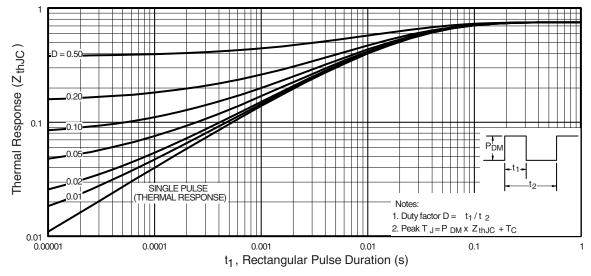


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



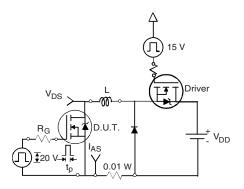


Fig. 12a - Unclamped Inductive Test Circuit

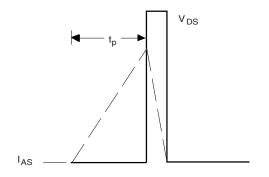


Fig. 12b - Unclamped Inductive Waveforms

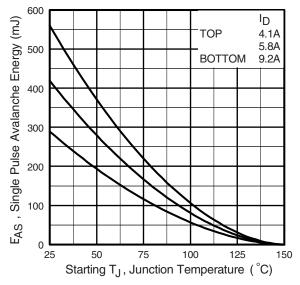


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

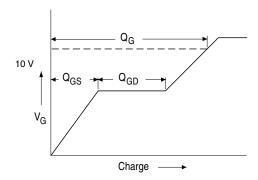


Fig. 13a - Basic Gate Charge Waveform

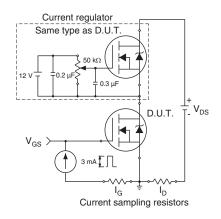
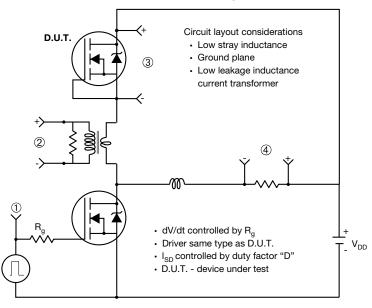


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



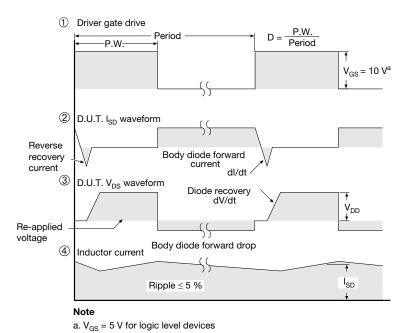
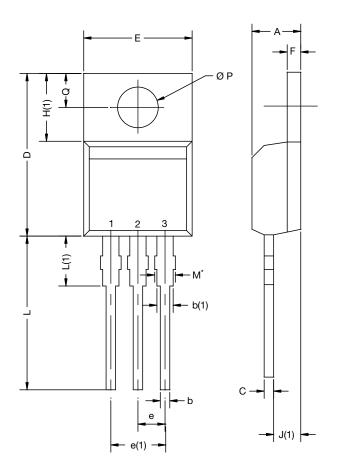


Fig. 14 - For N-Channel



TO-220-1



DIM.	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
Е	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031					

Note

 \bullet $M^{\star}=0.052$ inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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